FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

(use several sheets if necessary)

SERIAL NO.

09/939,498

FILING DATE
August 24, 2001

GROUP ART UNIT
2818

APPLICANT(S): Subramanian et al.

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REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING
DV C1	5,103,422	04/1992	Tokita et al.		DATE

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D		3,958,122	05/18/76	JOWETT 6	et al.	250	346	12/19/74
E		3,973,848	08/10/76	JOWETT 6		356	51	12/19/74
F			03/15/77	HEDELMAN		356	73	08/07/75
G	 	4,013,260	3/22/77		HIE et al.	250	343	09/27/74
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L		4,348,732	09/07/82	KREFT		364	571	
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	 	4,372,155	02/08/83	BUTLER 6		73	114	05/20/81
N	_	4,390,785	06/28/83		R et al.	250	330	12/29/80
0	ļļ	4,432,316	02/21/84	OGITA		123	328	09/14/81
Р		4,490,845	12/25/84		JEGGE et al.	382	1	02/02/82
Q		4,560,873	12/24/85	MCGOWAN		250	339	06/17/83
R		4,602,160	07/22/86	MACTAGGA		250	341	09/28/83
S	V	4,632,563	12/30/86	LORD, II		356	437	06/12/84
T		4,638,345	01/20/87	ELABD et	al.	357	24	06/01/83
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BB		ZHANG, Yi,	STEDMAN, D	onald H.	, BISHOP, Gary	A., BE	ATON, Stua	rt P.,
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		tor Mobile	Source Nit	ric Oxide	e"; Journal of	Air &	Waste Mana	igement [
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A	DV	5,210,702	05/11/93	BISHOP	et al	364	496	12/26/90
В	1	5,239,860	08/31/93	HARRIS		73	61.48	05/13/91
 	1	5,252,828	10/12/93	KERT et		250	339	04/07/92
D	 	5,255,511	10/26/93	MAUS et		60	274	09/18/92
E		5,307,626	05/03/94	MAUS et		60	274	09/18/92
F		5,319,199	06/07/94	STEDMAN		250	338.5	06/08/92
G		5,332,901	07/26/94	ECKLES (250	345	03/15/91
H		5,343,043	08/30/94	JOHNSON		250	338.5	09/13/93
Ī		5,361,171	11/01/94	BLEIER		359	855	03/04/93
J		5,371,367	12/06/94		ICO et al.	250	338.5	04/13/93
K		5,373,160	12/13/94	TAYLOR		250	338.5	05/04/93
L		5,401,967	03/28/95	STEDMAN		250	338.5	06/03/94
М		5,418,366	05/23/95	RUBIN et		250	338.5	05/05/94
N		5,489,777	02/06/96	STEDMAN		250	338.5	03/03/95
0		5,498,872	03/12/96	STEDMAN	et al.	250	338.5	04/21/95
Р		5,545,897	08/13/96	JACK		250	339.13	10/04/94
Q		5,583,765	12/10/96	KLEEHAM		364	423.098	08/23/94
R		5,591,975	07/07/97	JACK et	al.	250	338.5	10/05/94
S	<u> </u>	5,621,166	04/15/97	BUTLER		73	116	04/06/95
T	DV	5,644,133	07/01/97		CO et al.	250	338.5	07/25/95
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A	DV	5,719,396	02/17/98	JACK et	3	250	338.5	07/01/96
B	- ν <u>ν</u>	5,726,450	03/10/98	PETERSON		250	338.5	10/26/96
C	 }	5,797,682	08/25/98	KERT et		374	123	01/31/97
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G	ļ	6,057,923	05/02/00	SACHSE		356	364	04/13/99
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	B145	Schlaeppi, H.P., "Microsecond Core Memories Using Multiple Coincidence," 1960 International Solid-State Circuits Conference, Digest of Technical Papers, February 11, 1960, pages 54 - 55
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FORM PTO-1449	SERIAL NO.	CASE NO.
TOKWI TO THE	09/939,498	10519/30
LIST OF PATENTS AND RIVE CATIONS FOR	FILING DATE	GROUP ART UNIT
LIST OF PATENTS AND PHOSE CATIONS FOR APPLICANT'S INFORMATION DISCLOSURE	08/24/01	2818
STATEMENT		
(use several sheets if necessary)	APPLICANT(S): Subramanian e	et al.

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William _	10/16/02